**3GPP TSG-RAN WG4 Meeting #104-e draft R4-2214454**

**<Electronic Meeting>, 15 ‒ 26 August, 2022**

**Title:** WF on test metric for BC in RRC\_INACTIVE and initial access

**Agenda Item:** 11.7.4

**Source: Nokia**

**Document for:** Approval

# Sub-topic 1: Rel-16 RRC\_Connected Beam Correspondence applicability to Rel-18 RRC\_INACTIVE/IA Beam Correspondence

**Way forward/Agreements:**

* There is no UL beam sweep for IA BC requirements
* At least Msg1 will be tested.
* A new requirement is needed for Msg1 for all UEs regardless of Rel-16 BC IEs.
* If UEs support both IEs *beamCorrespondenceWithoutUL-BeamSweeping* and *beamCorrespondenceSSB-based-r16*, and performs IA with 4-step RACH then no new requirement is needed for Msg3
* Use PC3 as baseline for testing and requirements and handle specific values for other PC afterwards and based on the same method
* At least spherical coverage requirements will be tested for RRC\_Inactive Beam correspondence for Msg1
* Define a specific EIRP value at N% of the distribution of radiated power
* Discuss the value of N, e.g. N=[X]% for PC3

**Way forward/FFS:**

* FFS: Study the relevancy of adding min peak EIRP requirements in addition with spherical coverage requirements for BC Inactive (for each of the cases: Msg1/MsgA/RA-SDT/CG-SDT)
* FFS: values for the requirements (EIRP, X%, etc)
* FFS: Discuss whether BC requirements values will be the same for RA-SDT, CG-SDT and initial access (Msg1, MsgA, Msg 3), if yes should all be tested?
* FFS: Discuss whether Msg1 and Msg A should have the same requirements? If yes, should both be tested?
* FFS: BC side conditions

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| Company | Agree/Disagree, include justification |
| Qualcomm | We are not sure we need to redefine N % . We prefer to use the N specified for connected mode. Would proponents clarify why EIRP @ N must be studied again? (Do not agree to last 2 proposed agreements)  In the FFS list, why are we wanting to study the relevancy of min peak EIRP? (do not agree) |
| vivo | Before we figure out the baseline should be “rough” beam or “fine” beam and whether the beam refinement procedure is allowed during initial access, we can not agree the last 2 agreement above, and we prefer keep it open for further discussion. |
| Samsung | We agree with Qualcomm that the existing N% value of each power class should be reused, i.e. N=50% for PC3.  The same comment applys to the 2nd bullet of FFS list.  Besides beam correspondence test is at UE maximum output power in terms of testability, the beam correspondence requirements should also be specified at UE maximum output power. So we suggest to also capture this agreement in this WF for requirement perspective. |
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